

Application No. 09/832,642  
Amendment dated November 5, 2003  
Reply to Office action of July 2, 2003

**Amendments to the Specification:**

Please replace the paragraph beginning at page 5, line 24, with the following rewritten paragraph:

-- The present invention is a flexible spring tip 8 for a probe-type electrical tester. A general preferred embodiment of the flexible spring tip 8 of the present invention includes a flexible coil, tube, or spring 10 having a first end and a second end. The first end of the flexible spring 10 is for coupling with a device to be probed. A connector, such as a connecting pin 12, clip 12', or integral connector ~~13 (FIG. 7) 12"~~ (FIG. 4), is positioned at the second end of the flexible spring 10.--

Please replace the paragraph beginning at page 8, line 4, with the following rewritten paragraph:

--As mentioned, a connector is at the second end of the flexible spring 10. Most of the embodiments show a connecting pin 12 as the connector at the second end of the flexible spring 10. The connecting pin 12 is meant to be exemplary and any connector suitable for attaching to a probing head 13, signal socket 48, or grounding socket 22, may be used. The connecting pin 12 may be adapted to interact with any type of probe head (shown as probing head 13 in FIGS. 10-14). In the preferred embodiment shown in FIG. 2, the connecting pin 12 has a square cross section. A spring socket, clip 12' (FIG. 5), or other type of connector may be used in place of the connecting pin 12. Alternately, the flexible spring tip 8 may be integral (possibly using an integral connector 12") with the probing head 13 as shown in FIG. 4.--

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Please replace the paragraph beginning at page 9, line 10, with the following rewritten paragraph:

--FIG. 14 shows an embodiment of the flexible spring tip 8 with a foot 20 ~~foot~~ 14 (see also FIG. 9) that is particularly suited for attachment to the leads of an IC device. The flexible spring tip 8 may be attached to a grounding lead. The second probe tip 26 may then probe one or more other leads of the IC device 37. In other words, one flexible spring tip 8 may act as a grounding lead allowing the probing head to move and reach a plurality of leads.--